. •	,							
Substitute for	form 1449A/PTO & 1449	B/PTO	Com	Complete if Known				
• • •	SEC	COND	Application Number	09/508,430				
IN	FORMATIO	N DISCLOSURE	Filing Date	Filing Date March 13, 2000 First Named Inventor Meier, Rudolf et. al.				
SI	ATEMENT	BY APPLICANT	First Named Inventor					
	(use as many si	neets as necessary)	Examiner Name	H. Akhavannik				
Shed		of 1	Attorney Docket Number	030705-164				
6	- mak w							
Nº.	15 De E	U.S. PATENT DOCUMENTS						
Exambiner	Document	Kind Code	Name of Patentee or Applica	ent	Jesus/Bublication Date			

APR 0.5 DEM				
Examiner Initials	Document TRANSPRIDER	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)
			REC	CEIVED
			APR	0 9 2004
			Technolo	gy Center 2600

	FOREIGN PATENT DOCUMENTS									
E	xaminer Initials	Document Number	Kind Code (if known)	Country		Date of Publication (MM-DD-YYYY)	Translation			
	3.N	0491954	A1				DO6 H	3/08		
-										
\vdash										
\vdash										
								<u></u>		

	NON-PATENT LITERATURE DOCUMENTS						
Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.						
5.N	B. Nickolay, et al., "Automatic Textile Inspection", Studie fur die Textilindustrie, 60 pages, June 1993 E. Ersü, et al., "Rationelle 100% Optische Kontrolle in Der Vlies – Und Textilstoffproduktion", ISRA Systemtechnik GmbH, 16 pages						
V	Ferdinand van der Heijden, "Statistical Pattern Classification and Parameter Estimation", Image Based Measurement Systems, Object Recognition and Parameter Estimation, John Wiley & Sons, 1994						

Examiner	31)2//2	moran	Date	608-08
Signature	0.0000		Considered	070
*EXAMINER	Initial if reference considered	whether or not citation is in co	oformance with M P E P	6 600 Draw line through citation if not in

EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

RECEIVED HEET 1 OF 1

INFC	ORMATION	DISPLE	-SUR	ATTORNEY'S DKT NO MAY 1 APPLICATION NO. 030705-164 94509,430 APPLICANT Rudolf MEIER et a Group 2700				
			102000 質	FILING DATE		GROUP		
, s. s	PTO-1	1449	IS. PATENTIDO	March 13, 2000		Unassigned		
EXAMINER'S	T		P. A. C. L.	ŞĞÛMÊN12		1 · · · · · · · · · · · · · · · · · · ·	Telling	DATE
INITIALS	PATENT NO.	DATE		NAME	CLASS	SUBCLASS	FILING	
H.A.	5,544,256	08/1996	Brecher et al.		382	149		
		 					<u> </u>	
				- <u> </u>				
							 	
					 	 	 	
				<u> </u>	 		+	
					 	 	+	
	<u> </u>		 		 	<u> </u>	┼	
		 	 				<u> </u>	
			•	aliti		<u></u>	<u></u>	
EXAMINER'S	<u> </u>	FUR	EIGN PATENT	DOCUMENTS	1	i i	Tenn	slation
INITIALS	PATENT NO.	DATE		UNTRY	CLASS	SUBCLASS	Yes	No
<u> H.A.</u>	36 39 636	05/1988	Germany					X
H.A.	0 491 954	07/1992	Europe				in English	
H.A.	2 701 766	08/1994	France					x
H.A.	2 253 697	09/1992	Great Britain				in English	
	OTHER DOC	UMENTS (In	cluding Author	Title, Date, Perti	inent Pag	es, Etc.)		EDĄ.
		_						
	A 1							
EXAMINER	M	<u>- X-</u>	A DA	ATE CONSIDERED	11/1	102		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.